74ACT11543 **OCTAL REGISTERED TRANSCEIVER** WITH 3-STATE OUTPUTS

SCAS136 - D3608, JULY 1990 - REVISED APRIL 1993

 Inputs Are TTL-Voltage Compatible 3-State True Outputs 	DW PAC (TOP V	
 Back-to-Back Registers for Storage 		
 Flow-Through Architecture Optimizes PCB Layout 	CEBA [1 A1 [2 A2 [3	28 GBA 27 LEBA 26 B1
 Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise 	A3 [4 A4 [5	25 B2 24 B3
 EPIC[™] (Enhanced-Performance Implanted CMOS) 1-µm Process 	GND [] 6 GND [] 7	23 B4 22 V _{CC}
 500-mA Typical Latch-Up Immunity at 125°C 	GND [8 GND [9	21 V _{CC} 20 B5
description	A5 🚺 10	19 B6
This 8-bit registered transceiver contains two sets of D-type latches for temporary storage of data flowing in either direction. Separate latch enable (LEAB or LEBA) and output enable (GAB or GBA)	A6 [] 11 A7 [] 12 A8 [] 13 CEAB [] 14	18 B7 17 <u>B8</u> 16 <u>LEAB</u> 15 <u>GAB</u>

The A-to-B enable (CEAB) input must be low in order to enter data from A or to output data to B. Having CEAB low and LEAB low makes the A-to-B latches transparent; a subsequent low-to-high transition of LEAB puts the A latches in the storage mode. With CEAB and GAB both low, the 3-state B outputs are active and reflect the data present at the output of the A latches. Data flow from B-to-A is similar, but requires the use of CEBA, LEBA, and GBA inputs.

	FUNCTION TABLE									
	INPUTS		LATCH STATUS	OUTPUT BUFFERS						
CEAB	LEAB	GAB	A TO B [†]	B1 THRU B8						
н	Х	Х	Storing	Z						
X	Н		Storing							
X		Н		Z						
L	L	L	Transparent	Current A Data						
L	Н	L	Storing	Previous [‡] A Data						

The 74ACT11543 is characterized for operation from -40° C to 85° C.

inputs are provided for each register to permit independent control in either direction of data flow.

> [†]A-to-B data flow is shown: B-to-A flow control is the same except uses CEBA, LEBA, and GBA.

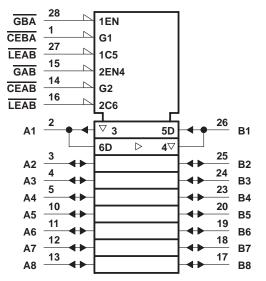
[‡] Data present before low-to-high transition of $\overline{\text{LEAB}}$.

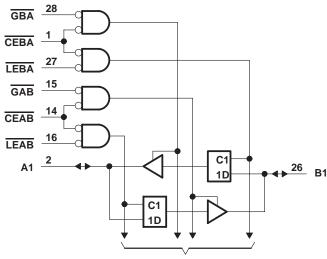
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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



logic symbol[†]





logic diagram (positive logic)

To Seven Other Transceivers

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	-0.5 V to V _{CC} + 0.5 V
Output voltage range, V _O (see Note 1)	-0.5 V to $V_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	± 20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	± 50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	± 50 mA
Continuous current through V _{CC} or GND	± 200 mA
Storage temperature range	–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for excluded periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
VI	Input voltage	0		VCC	V
Vo	Output voltage	0		VCC	V
ЮН	High-level output current			-24	mA
I _{OL}	Low-level output current			24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	ns/V
TA	Operating free-air temperature	- 40		85	°C



	ADAMETED		Vcc	T _A = 25°C			MIN	МАХ	UNIT
PARAMETER		TEST CONDITIONS		MIN	TYP	MAX			UNIT
		I _{OH} = - 50 μA	4.5 V	4.4			4.4		
			5.5 V	5.4			5.4		
Vон		Jac. 24 mA	4.5 V	3.94			3.8		V
		I _{OH} = – 24 mA	5.5 V	4.94			4.8		
		I _{OH} = - 75 mA [†]	5.5 V				3.85		
		1	4.5 V			0.1		0.1	
		I _{OL} = 50 μA	5.5 V			0.1		0.1	
VOL		I _{OL} = 24 mA	4.5 V			0.36		0.44	V
			5.5 V			0.36		0.44	
		I _{OL} = 75 mA [†]	5.5 V					1.65	
I	Control inputs	V _I = V _{CC} or GND	5.5 V			± 0.1		± 1	μΑ
I _{OZ}	A or B ports‡	$V_{O} = V_{CC}$ or GND	5.5 V			± 0.5		± 5	μΑ
ICC	-	$V_{I} = V_{CC} \text{ or } GND, I_{O} = 0$	5.5 V			8		80	μΑ
AICC	§	One input at 3.4 V, Other inputs at GND or V_{CC}	5.5 V			0.9		1	mA
Ci	Control inputs	V _I = V _{CC} or GND	5 V		4.5				pF
Cio	A or B ports	$V_{O} = V_{CC}$ or GND	5 V		12				pF

electrical characteristics over recommended operating free-air temperature range

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

[‡] For I/O ports, the parameter I_{OZ} includes the input leakage current.

§ This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

			T _A = 25°C		T _A = 25°C MIN MA		MAX	UNIT
			MIN	MAX	WIIN	IVIAA	UNIT	
tw	t _w Pulse duration, LEAB or LEBA low		4		4		ns	
	Setup time	Data after LEAB or LEBA	2.5		2.5		ns	
tsu	Setup time	Data before CEAB or CEBA↑	3		3		115	
÷.	Hold time	Data after LEAB or LEBA	2		2		20	
th Hold time	Hold time Data after CEAB or CEBA↑	Data after CEAB or CEBA↑	1.5		1.5		ns	



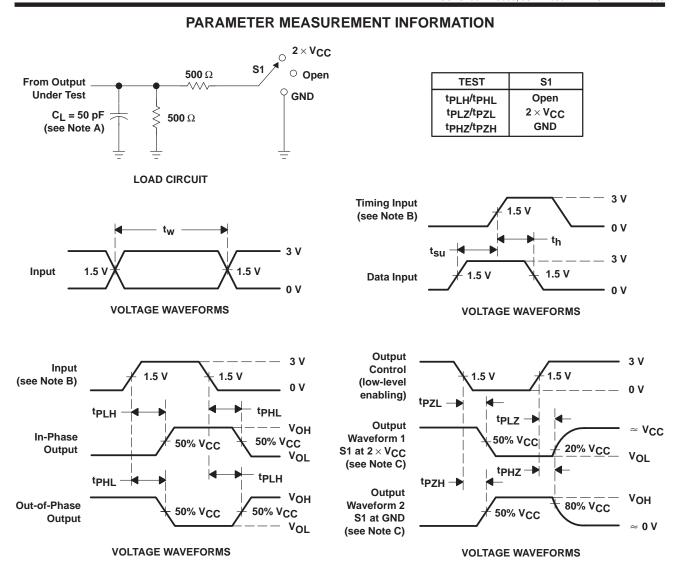
switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Т	₄ = 25°C	;	MIN	МАХ	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX		WIAA	UNIT
^t PLH	A or B	B or A	3.5	6.2	9.1	3.5	10.2	ns
^t PHL	AUB	BUIA	3.2	6.5	10.8	3.2	12.1	115
^t PLH	LEBA or LEAB	A or B	3	6.1	10.1	3	11.2	20
^t PHL		AUID	3.7	7.2	11.7	3.7	13.2	ns
^t PZH	CEBA or CEAB	A or B	3.5	6.7	11.1	3.5	12.2	ns
^t PZL		AUB	3.2	8.4	13.4	3.2	16	115
^t PHZ		A or B	4.8	7.3	10.1	4.8	11	ns
^t PLZ	CEBA or CEAB	AUB	5.1	7.5	10.3	5.1	11.1	115
^t PZH		A or B	3.3	6.4	10.5	3.3	11.5	ns
tPZL	GBA or GAB	AUB	3	8	12.8	3	15.3	115
^t PHZ		A or B	4.6	6.9	9.6	4.6	10.4	20
^t PLZ	GBA or GAB	AUB	5	7.1	9.8	5	10.5	ns

operating characteristics, $V_{CC} = 5 V$, $T_A = 25^{\circ}C$

PARAMETER		TEST CON	TYP	UNIT	
C _{pd}	Dower dissinction conscitutes per transcriver	Outputs enabled	C _L = 50 pF, f = 1 MHz	47	ьE
	Power dissipation capacitance per transceiver	Outputs disabled			13





NOTES: A. CL includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f = 3 ns, t_f = 3 ns.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
- Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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